


<b>Search Notes</b>  	<b>Application/Control No.</b>  10015613	<b>Applicant(s)/Patent Under Reexamination</b>  BAUDISCH, PATRICK
	<b>Examiner</b>  AARON M RICHER	<b>Art Unit</b>  2628

### SEARCHED

Class	Subclass	Date	Examiner
345	1.3-3.4 (text search only) - updated	5/10/08	AMR
Above	Updated	9/27/08	AMR

### SEARCH NOTES

Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - updated - see search history	5/10/08	AMR
Updated	9/27/08	AMR

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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